IAP20 Rec'd PGT/FTO 24 JAN 2006

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Applicants:

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Attorney Docket No.: NAII127017

Title:

SCANNING PROBE MICROSCOPE

U.S. PATENT DOCUMENTS

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None

FOREIGN PATENT DOCUMENTS

*Examine	r Cite		Kind	Publication Date		English	
Initial	No.	Document No.	Code	(mm/dd/yyyy)	Country	Abstract Provided	Translation Provided
	F1	JP 5-52546	Α	03/02/1993	JP	X	X
	F2	JP 8-170906	Α	07/02/1996	JP	X	X
	F3	JP 10-142241	Α	05/29/1998	JP	X	X
	F4	JP 2001-324440	Α	11/22/2001	JP	X	X
	F5	JP 2003-98061	Α,	04/03/2003	JР	X	X

OTHER INFORMATION

(Including Author, Title, Date, Pertinent Pages, Etc.)

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None

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